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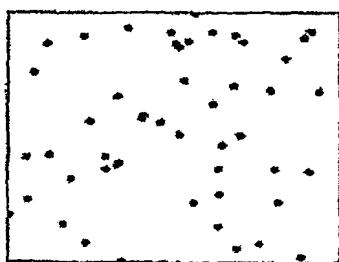
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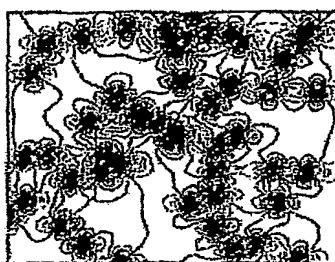
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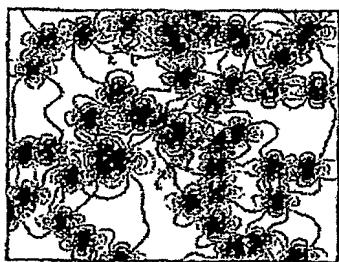
(54) Title: METHOD, SYSTEM AND SOFTWARE ARRANGEMENT, FOR MEASURING MAGNETIC FIELD CORRELATION



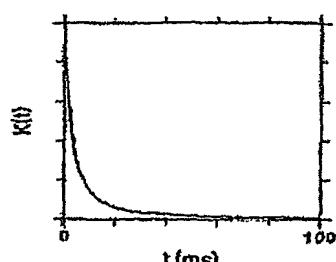
(a)



(b)



(c)



(d)

(57) Abstract: Methods, systems, software arrangements and storage medium for measuring the magnetic field correlation function ("MFC"), and more particularly, to methods for measuring the magnetic field correlation function utilizing asymmetric spin echoes. Asymmetric Dual Spin Echo Sequences ("ADSE") and Echo Planar Imaging Asymmetric Dual Spin Echo Sequences ("EPI-ADSE") may be employed to apply multiple echoes to a sample and acquire data from which the MFC may be determined.

WO 2005/008259 A2



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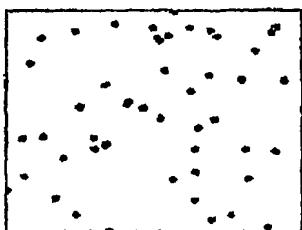
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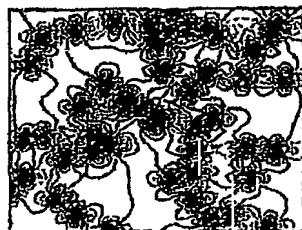
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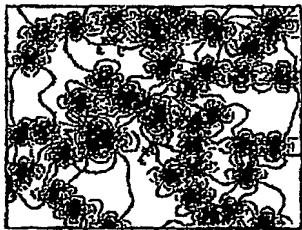


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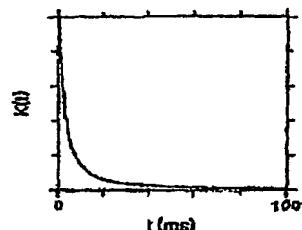


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